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Dated: December 28, 2006 Signature:

*Tina M. Dougal*  
(Tina M. Dougal)

Docket No.: 0002802.00169US1  
(PATENT)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant: Martin W. Rupich et al. Confirmation No.: 3570  
Application No.: 10/812,676 Art Unit: 1722  
Filed: March 30, 2004 Examiner: R. M. Kunemund  
Title: DEPOSITION OF BUFFER LAYERS ON TEXTURED METAL SURFACES

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
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**INFORMATION DISCLOSURE STATEMENT (IDS)**

Dear Sir:

This Information Disclosure Statement is being filed simultaneously with a Request for Continued Examination. No fee is believed to be due.

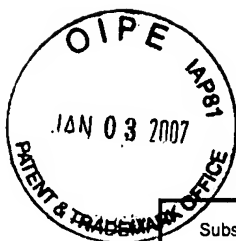
Applicants request that the Examiner initial and return a copy of the enclosed Form PTO SB-08 with the next communication.

Respectfully submitted,

Dated: December 28, 2006

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PTO/SB/08A/B (09-06)

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**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet	1	of	2	Attorney Docket Number	0002802.00169US1
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**Complete if Known**

Application Number	10/812,676-Conf. #3570
Filing Date	March 30, 2004
First Named Inventor	Martin W. Rupich
Art Unit	1722
Examiner Name	R. M. Kunemund

**U.S. PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
	AA	US-08/943,047	10-01-1997	Thieme	
	AB	US-09/007,373	01-15-1998	Fritzemeier et al.	
	AC	US-60/447,613	06-10-2003	Rupich et al.	
	AD*	US-2002/0056401-A1	05-16-2002	Rupich et al.	
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	AG*	US-2003/0130129-A1	07-10-2003	Seleznev et al.	
	AH*	US-2005/0016759-A1	01-27-2005	Malozemoff et al.	
	AI*	US-2005/0159298-A1	07-21-2005	Rupich, et al.	
	AJ*	US-5,231,074	07-27-1993	Cima et al.	
	AK*	US-5,340,794	08-23-1994	Tallon et al.	
	AL*	US-6,022,832	02-08-2000	Fritzemeier et al.	
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	AN*	US-6,202,287	03-20-2001	Otto	
	AO*	US-6,399,154	06-04-2002	Williams et al.	
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	AX*	US-6,745,059-A1	06-01-2004	Buczek et al.	
	AY*	US-6,797,313	09-28-2004	Fritzemeier et al.	
	AZ*	US-6,828,507	12-07-2004	Fritzemeier et al.	
	AA1*	US-6,974,501-B1	12-13-2005	Zhang et al.	

**FOREIGN PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)				
	BA	WO-98/58415	12-23-1998	Massachusetts Institute of Technology		
	BB	WO-99/25908	05-27-1999	The Board of Trustees of the Leland Stanford Junior University		
	BC	WO-01/08236	02-01-2001	American Superconductor Corporation		

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. \* CITE NO.: Those application(s) which are marked with an single asterisk (\*) next to the Cite No. are not supplied (under 37 CFR 1.98(a)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IFW. <sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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Substitute for form 1449/PTO				<b>Complete if Known</b>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)				Application Number	10/812,676-Conf. #3570
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				Art Unit	1722
				Examiner Name	R. M. Kunemund
Sheet	2	of	2	Attorney Docket Number	0002802.00169US1

NON PATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		T <sup>2</sup>
	CA	EUROPEAN PATENT OFFICE, International Search Report of PCT/US2005/010593 mailed 14 November 2005, 3 pages		
	CB	PARANTHAMAN, M. et al, "Growth of Textured Buffer Layers and Superconductors on Rolled Ni Substrates Using Sol-gel Alkoxide Precursors", Ninth CIMTEC World Ceramics Contress and Forum on New Materials, Florence, Italy, 1998, pp. 185-192		
	CC	PARANTHAMAN, S. et al, "Epitaxial Growth of BaZrO <sub>3</sub> Films on Single Crystal Oxide Substrates Using Sol-Gel Alkoxide Precursors", Mater. Res. Bull., Vol. 32, No. 12, 1997, pp. 1697-1704		
	CD	SATHYAMURTHY et al, "Application of Metal-Organic Decomposition Techniques for the Deposition of Buffer Layers and Y123 for Coated-Conductor Fabrication", Physica C (Netherlands), 2000, Vol. 329, pp. 58-68		
	CE	SATHYAMURTHY et al, "Chemical Solution Deposition of Highly Oriented Strontium Titanate Buffer Layers for Coated Conductors", Supercond. Sci. Technol., 2000, Vol. 13, pp. L1-L3		
	CF	SCHWARTZ, "Control of Microstructure and Orientation in Solution-Deposited BaTiO <sub>3</sub> and Sr TiO <sub>3</sub> Thin Films", J. Am. Ceram. Soc., 1999, Vol. 82, No. 9, pp. 2359-2367		
	CG	SHOUP et al, "Sol-Gel Synthesis of LaAlO <sub>3</sub> ; Epitaxial Growth of LaAlO <sub>3</sub> Thin Films on SrTiO <sub>3</sub> (100)", J. Mat. Research, 1997, Vol. 12, pp. 1017-21		

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>Applicant is to place a check mark here if English language Translation is attached.

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